

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/670,262	YOUN, KARP-SIK	
Examiner	Art Unit	
Vicky A. Johnson	3682	

SEARCHED				
Class	Subclass	Date	Examiner	
474	109			
	114			
	115			
	117			
347	37-39			
	54,86			
	91			
403	13,14			
	283,278	7/19/2005	VAJ	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	I				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Hai Phan 347		
Rachel Dicht 347		
Ernesto Garcia 403	7/19/2005	VAJ
INventor name search	7/19/2005	VAJ
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